

Notice of References Cited	Application/Control No. 10/525,929	Applicant(s)/Patent Under Reexamination SEKI ET AL.	
	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,043,180 A	03-2000	Jacobsen et al.	502/103
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kopf et al. Cryst. Struct. Comm., 1980, 9, 985-990.
	V	Brackemeyer et al. Organometallics 1997, 16,531-536. ✓
	W	Edelbach et al. Organometallics 1999, 18, 3170-3177. ✓
	X	Lukens et al. Organometallics 1995, 14, 3435-3439. ✓

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/525,929

Applicant(s)/Patent Under
Reexamination
SEKI ET AL.

Examiner

Rip A. Lee

Art Unit

1713

Page 2 of 2


U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Schmid et al. J. Organomet. Chem. 1997, 544(1), 139-142 (abstract). ✓
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.